# Product Change Notification - JAON-04UCYV212

Memory

Date: 12 Jan 2017 **Product Category:** 

Notification subject: CCB 2745 Final Notice: Qualification of 35.8K process technology for selected products of the

25xx128 and 25xx256 device families available in 8L TSSOP package.

**PCN Status:** Notification text: Final notification

**Microchip Parts Affected:** 

Please open the attachments found in the attachments field below labeled as PCN # Affected CPN.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

# **Description of Change:**

Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.

#### Pre Change:

Available in 160K wafer technology fabricated at Microchip fabrication sites FAB2 and FAB4 (Tempe, AZ and Gresham, OR, USA) using 8 inch wafers

#### **Post Change:**

Available in 160K wafer technology fabricated at Microchip fabrication sites FAB2 and FAB4 (Tempe. AZ and Gresham. OR. USA) using 8 inch wafers or available in 35.8K wafer technology fabricated at FAB 5 (Colorado Springs, CO, USA) using 6 inch wafers

# **Pre and Post Change Summary:**

	Pre Change	Post Change				
Wafer Technology	160K wafer technology	160K wafer technology	35.8K wafer technology			
Fabrication Location	Microchip Fabrication Sites FAB 2 and FAB4 (Tempe, AZ and Gresham, OR, USA)	Microchip Fabrication Sites FAB 2 and FAB4 (Tempe, AZ and Gresham, OR, USA)	FAB 5 (Colorado Springs, CO USA)			
Wafer Diameter	8 inches (200 mm)	8 inches (200 mm)	6 inches (150 mm)			
Quality certification	ISO/TS16949	ISO/TS16949	ISO9001/TS16949			

#### **Impacts to Data Sheet:**

None

## **Change Impact:**

None

#### **Reason for Change:**

To improve manufacturability by qualifying an additional fabrication site.

## **Change Implementation Status:**

In Progress

**Estimated First Ship Date:** 

February 13, 2017 (date code: 1707)

NOTE:

In order to receive products only fabricated with the current 160K process please use the revised part number identified with RVA added to the end of the part number (see example below).

Standard Part Number: 25xx128x-x/xx or 25xx256x-x/xx

Revised Part Number (160K only): 25xx128x-x/xxRVA or 25xx256x-xx/xxRVA

# **Time Table Summary:**

	December 2016			January 2017			February 2017						
Workweek	48	49	50	51	52	01	02	03	04	05	06	07	08
Initial PCN Issue Date		Χ											
Qual Report Availability							Χ						
Final PCN Issue Date							Χ						
Estimated Implementation Date												Χ	

# Method to Identify Change:

Traceability code

**Qualification Report:** 

Please open the attachments included with this PCN labeled as PCN\_#\_Qual Report.

**Revision History:** 

December 6, 2016: Issued initial notification.

**January 12, 2017**: Issued final notification. Attached the qualification report. Provided estimated first ship date to be on February 13, 3017.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s): PCN\_JAON-04UCYV212\_Qual Report.pdf

PCN\_JAON-04UCYV212\_Affected CPN.pdf PCN\_JAON-04UCYV212\_Affected CPN.xls

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JAON-04UCYV212 - CCB 2745 Final Notice: Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.

Affected Catalog Part Numbers (CPN)

PCN_JAON-04UCYV212
CATALOG_PART_NBR
25AA256-I/ST
25AA256T-I/ST
25LC256-E/ST
25LC256-I/ST
25LC256T-E/ST
25LC256T-I/ST
25AA128-I/ST
25AA128T-I/ST
25LC128-E/ST
25LC128-I/ST
25LC128T-E/ST
25LC128T-I/ST



# **QUALIFICATION REPORT SUMMARY**

**RELIABILITY LABORATORY** 

PCN #: JAON-04UCYV212

Date January 05, 2017

Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.



**Purpose** Qualification of 35.8K process technology for selected products of the

25xx128 and 25xx256 device families available in 8L TSSOP package.

**CN** ES080013

QUAL ID Q16179

 MP CODE
 358A24C5XA00

 Part No.
 25LC256-E/ST

Bonding No. BDE-003951 Rev. 01

**CCB No.** 2745

**Package** 

Type 8L TSSOP

Package size 4.4 mm

Die thickness 11 mils

**Die size** 57.10 x 69.50 mils

**Lead Frame** 

Paddle size 118 x 87 mils

Material C7025

Surface Ag spot plated

Process Stamped

Lead Lock No

**Part Number** 10100821

Treatment None

Die attach material

Epoxy 2200D
Wire Au wire
Mold Compound G600V
Plating Composition Matte Tin



# **Manufacturing Information**

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-173000404.000	MCSO917225494.400	1642JUU
MMT-173000765.000	MCSO917225494.400	1642PVU
MMT-173000814.000	MCSO917225494.400	1642Q5P

Result	X Pass	Fail	
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8L TSSOP (4.4 mm) assembled by MMT pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

PACKAGE QUALIFICATION REPORT							
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks	
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020D)	IPC/JEDE C J-STD- 020D	135	0/135	Pass		

Precondition Prior Perform	Electrical Test :+25°C,85°C and 125°C System: NEXTEST_PT	JESD22- A113	693(0)	693		Good Devices
Reliability Tests (At MSL Level 1)	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max			693		
	System: Vitronics Soltec MR1243					
	<b>Electrical Test :</b> +25°C,85°C and 125°C System: NEXTEST_PT			0/693	Pass	

PACKAGE QUALIFICATION REPORT							
Test Number	Test Condition	Standard/	Qty.	Def/SS.	Result	Remarks	
(Reference)		Method	(Acc.)				
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H	JESD22- A104		231		Parts had been pre-conditioned at 260°C	
Temp Cycle	<b>Electrical Test:</b> + 85°C and 125°C System: NEXTEST_PT		231(0)	0/231	Pass	77 units / lot	
	Bond Strength: Wire Pull (> 2.5 grams)		15 (0)	0/15	Pass		
	Bond Shear (>15.00 grams)		15 (0)	0/15	Pass		
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C	
	Electrical Test: +25°C System: NEXTEST_PT		231(0)	0/231	Pass	77 units / lot	
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X	JESD22- A110		231		Parts had been pre-conditioned at 260°C	
1,7,61	Electrical Test:+25°C,85°C and 125°C System: NEXTEST_PT		231(0)	0/231	Pass	77 units / lot	
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units	
	Electrical Test :+25°C,85°C and 125°C System: NEXTEST_PT		45(0)	0/45	Pass		

	PACKAGE QUALIFICATION REPORT							
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks		
Bond Strength	Wire Pull (> 2.5 grams)	M2011	30 (0) Wires	0/30	Pass			
Data Assembly	Bond Shear (>15.00 grams)	JESD22- B116	30 (0) bonds	0/30	Pass			